

4/23/2015



**RELIABILITY MONITOR REPORT
FOR**

San Antonio 0.5 μ m Silicon Gate (E35)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX5128ELA+T

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 7945 QUANTITY: 48 FAILS: 0 FITS: 14.4

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2014 and 3/31/2015 .

Process Information:

Process Description: San Antonio 0.5µm Silicon Gate (E35)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1417	MAX5128ELA+T	135°C	1000 HRS	48	0	TAKQ8A025CB
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1417	MAX5128ELA+T	150°C	1000 HRS	66	0	TAKQ8A025CB
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1417	MAX5128ELA+T	-65C TO +150C (Condition C)	1000 CYS	78	0	TAKQ8A025CB
Total:						0	

FAILURE RATE: MTTF (YRS): 7945 QUANTITY: 48 FAILS: 0 FITS: 14.4